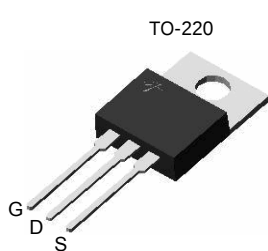


AOT8N60 / AOTF8N60
600V, 8A N-Channel MOSFET

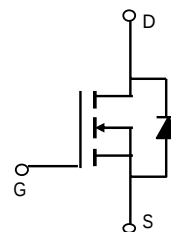
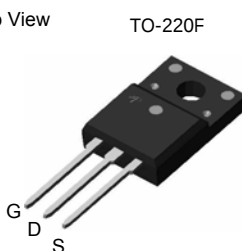
formerly engineering part number AOT9606/AOTF9606


General Description

The AOT8N60 & AOTF8N60 have been fabricated using an advanced high voltage MOSFET process that is designed to deliver high levels of performance and robustness in popular AC-DC applications. By providing low $R_{DS(on)}$, C_{iss} and C_{rss} along with guaranteed avalanche capability these parts can be adopted quickly into new and existing offline power supply designs.

Features
 $V_{DS} (V) = 700V @ 150^{\circ}C$
 $I_D = 8A$
 $R_{DS(ON)} < 0.9 \Omega (V_{GS} = 10V)$
100% UIS Tested!
100% R_g Tested!
 C_{iss} , C_{oss} , C_{rss} Tested!


Top View


Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter	Symbol	AOT8N60	AOTF8N60	Units
Drain-Source Voltage	V_{DS}	600		V
Gate-Source Voltage	V_{GS}	± 30		V
Continuous Drain Current ^B	$T_C=25^{\circ}C$	8	8*	A
	$T_C=100^{\circ}C$	5	5*	
Pulsed Drain Current ^C	I_{DM}	32		
Avalanche Current ^C	I_{AR}	3.2		A
Repetitive avalanche energy ^C	E_{AR}	150		mJ
Single pulsed avalanche energy ^G	E_{AS}	300		mJ
Peak diode recovery dv/dt	dv/dt	5		V/ns
Power Dissipation ^B	$T_C=25^{\circ}C$	147	50	W
	Derate above 25°C	1.17	0.4	W/°C
Junction and Storage Temperature Range	T_J, T_{STG}	-50 to 150		°C
Maximum lead temperature for soldering purpose, 1/8" from case for 5 seconds	T_L	300		°C

Thermal Characteristics

Parameter	Symbol	AOT8N60	AOTF8N60	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	65	65	°C/W
Maximum Case-to-Sink ^A	$R_{\theta CS}$	0.5	-	°C/W
Maximum Junction-to-Case ^{D,F}	$R_{\theta JC}$	0.85	2.5	°C/W

* Drain current limited by maximum junction temperature.

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0V, T _J =25°C	600			V
		I _D =250μA, V _{GS} =0V, T _J =150°C		700		V
BV _{DSS} /ΔT _J	Breakdown Voltage Temperature Coefficient	I _D =250μA, V _{GS} =0V		0.65		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =600V, V _{GS} =0V			1	μA
		V _{DS} =480V, T _J =125°C			10	
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±30V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	3	3.8	5	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =4A		0.74	0.9	Ω
g _{FS}	Forward Transconductance	V _{DS} =40V, I _D =4A		12.5		S
V _{SD}	Diode Forward Voltage	I _S =1A, V _{GS} =0V		0.73	1	V
I _S	Maximum Body-Diode Continuous Current				8	A
I _{SM}	Maximum Body-Diode Pulsed Current				32	A
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =25V, f=1MHz	912	1140	1370	pF
C _{oss}	Output Capacitance		87	109	131	pF
C _{rss}	Reverse Transfer Capacitance		6.2	7.8	9.5	pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz	3.1	3.9	5.9	Ω
SWITCHING PARAMETERS						
Q _g	Total Gate Charge	V _{GS} =10V, V _{DS} =480V, I _D =8A		28.4	35	nC
Q _{gs}	Gate Source Charge			5.8	7	nC
Q _{gd}	Gate Drain Charge			13.4	17	nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =10V, V _{DS} =300V, I _D =8A, R _G =25Ω		30	40	ns
t _r	Turn-On Rise Time			63	75	ns
t _{D(off)}	Turn-Off DelayTime			69	85	ns
t _f	Turn-Off Fall Time			51	65	ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =8A, dI/dt=100A/μs, V _{DS} =100V		270	324	ns
Q _{rr}	Body Diode Reverse Recovery Charge	I _F =8A, dI/dt=100A/μs, V _{DS} =100V		3.3	4.0	μC

A: The value of R_{θJA} is measured with the device in a still air environment with T_A=25°C.

B: The power dissipation P_D is based on T_{J(MAX)}=150°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature T_{J(MAX)}=150°C.

D: The R_{θJA} is the sum of the thermal impedance from junction to case R_{θJC} and case to ambient.

E: The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

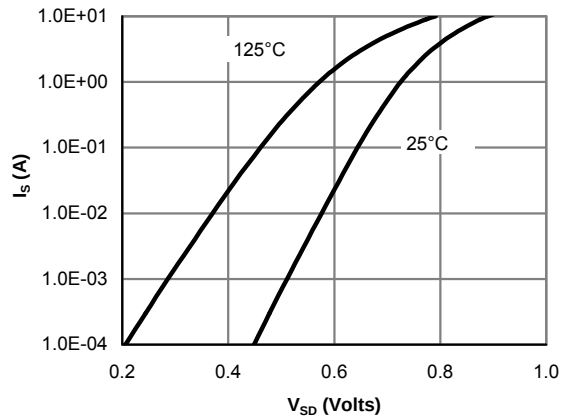
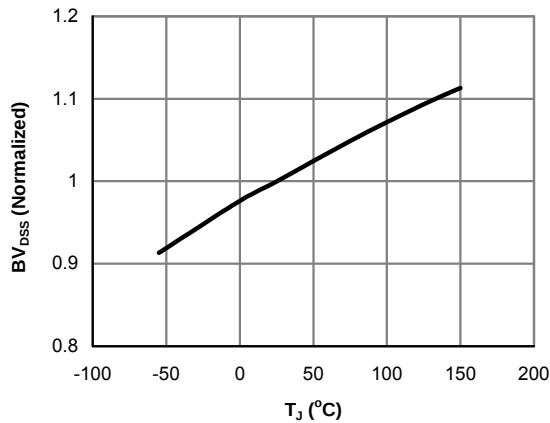
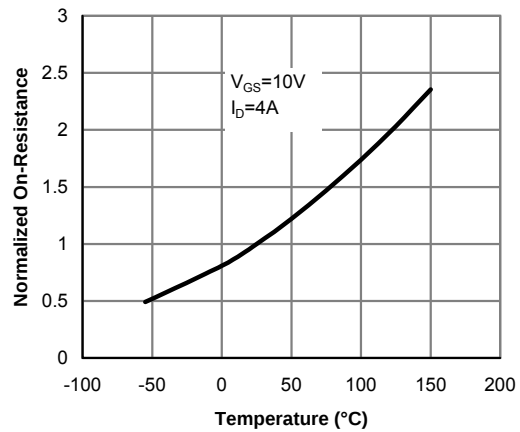
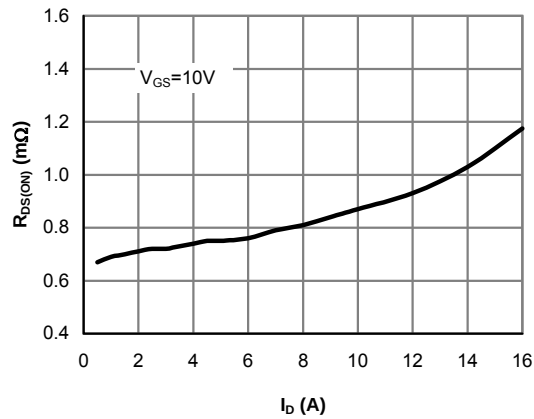
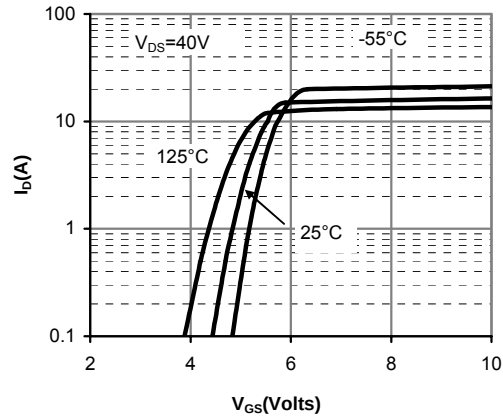
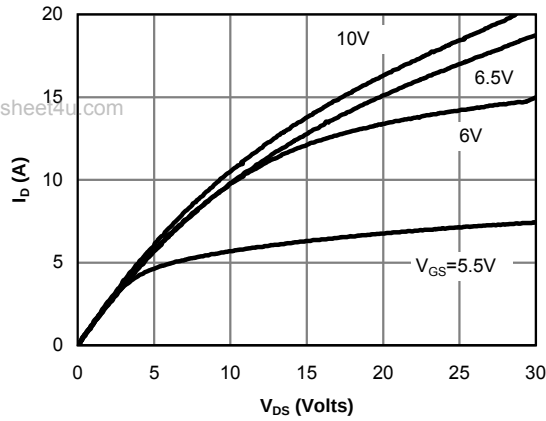
F: These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T_{J(MAX)}=150°C.

G: L=60mH, I_{AS}=3.2A, V_{DD}=50V, R_G=25Ω, Starting T_J=25°C

Rev 0. July 2008

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

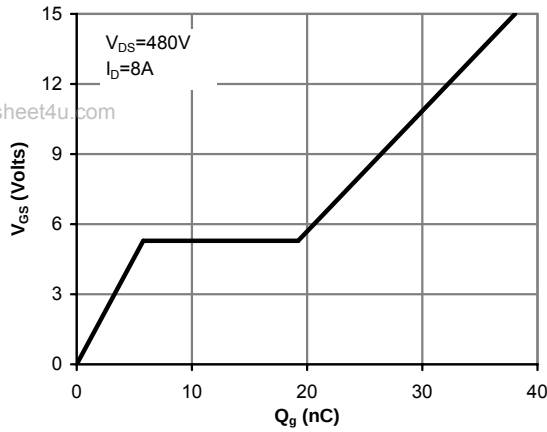


Figure 7: Gate-Charge Characteristics

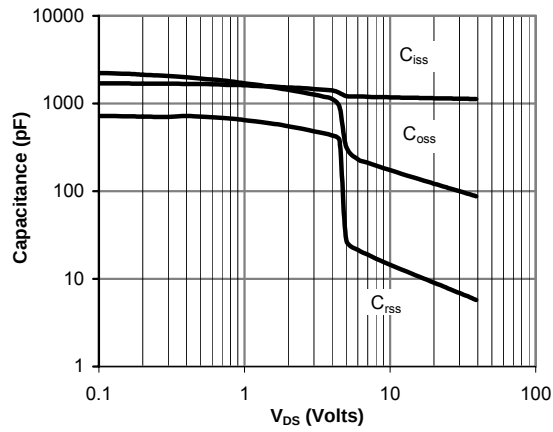


Figure 8: Capacitance Characteristics

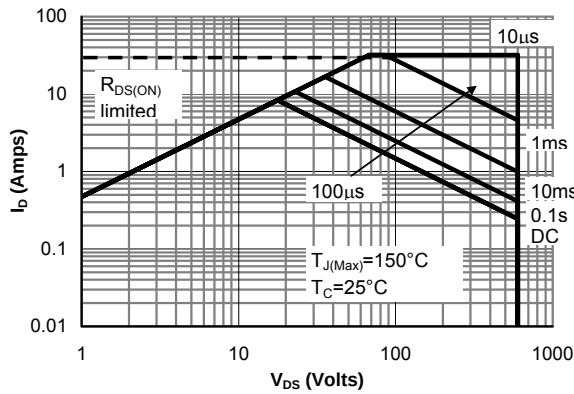


Figure 9: Maximum Forward Biased Safe Operating Area for AOT8N60 (Note F)

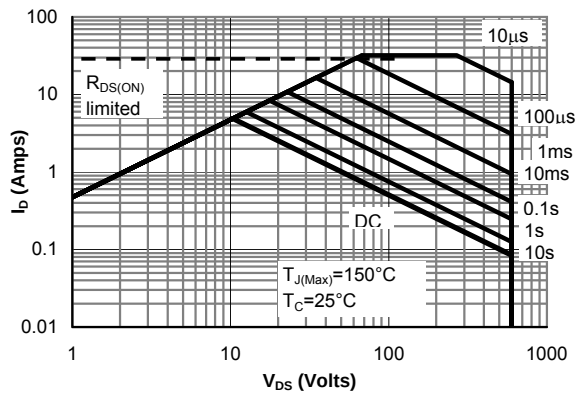


Figure 10: Maximum Forward Biased Safe Operating Area for AOTF8N60 (Note F)

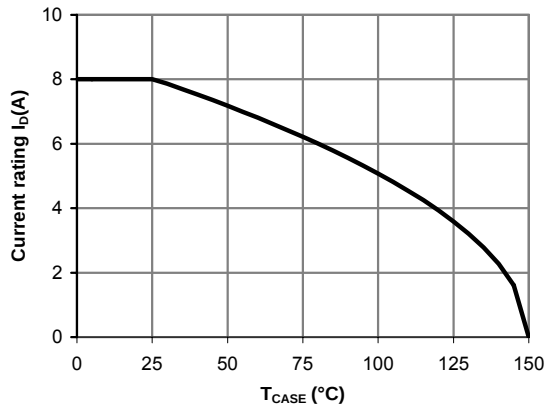


Figure 11: Current De-rating (Note B)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

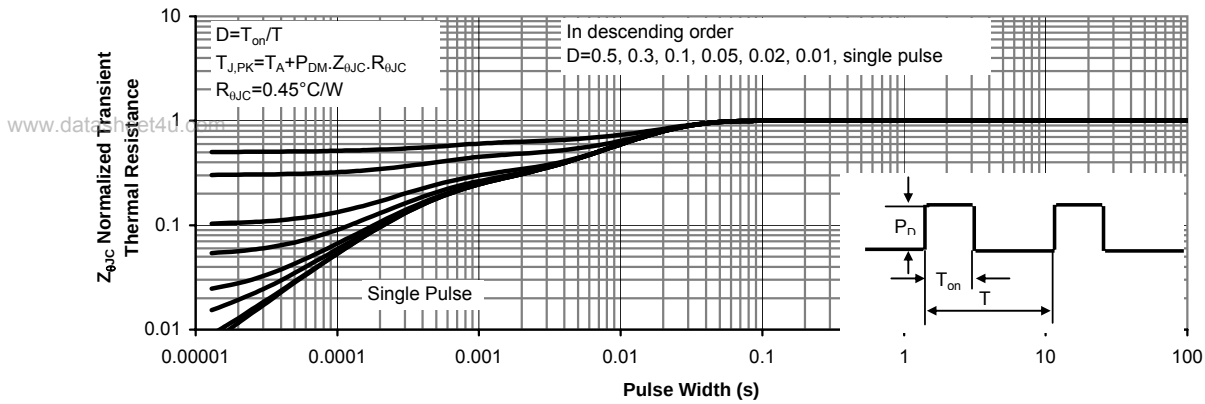


Figure 12: Normalized Maximum Transient Thermal Impedance for AOT8N60 (Note F)

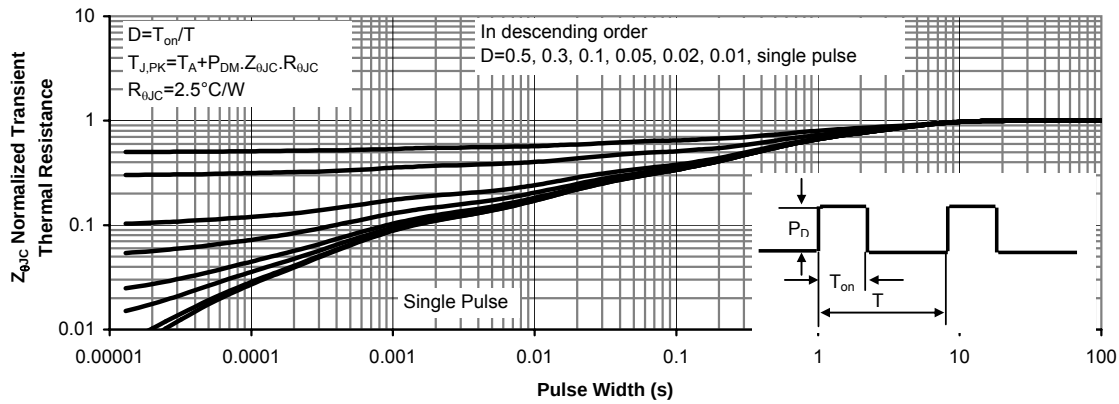
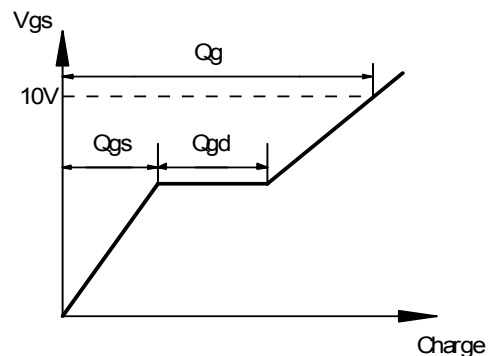
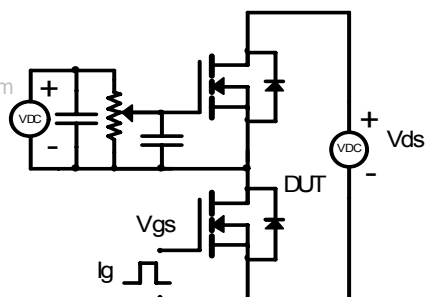


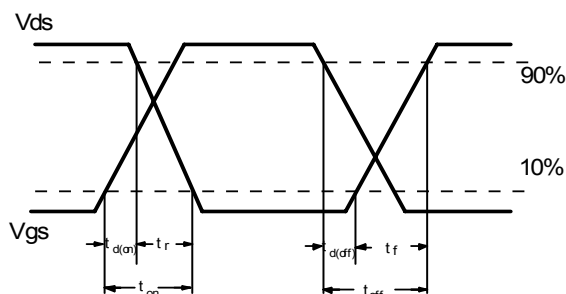
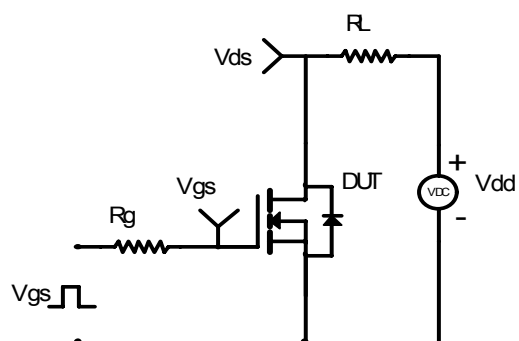
Figure 13: Normalized Maximum Transient Thermal Impedance for AOTF8N60 (Note F)

Gate Charge Test Circuit & Waveform

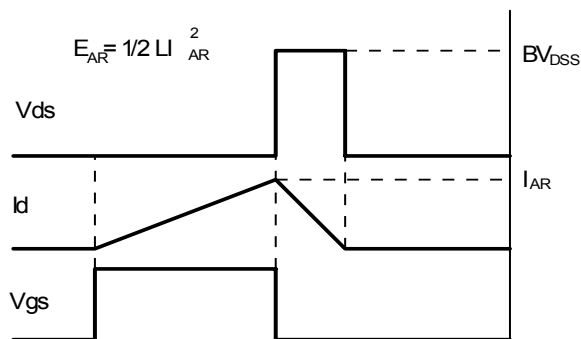
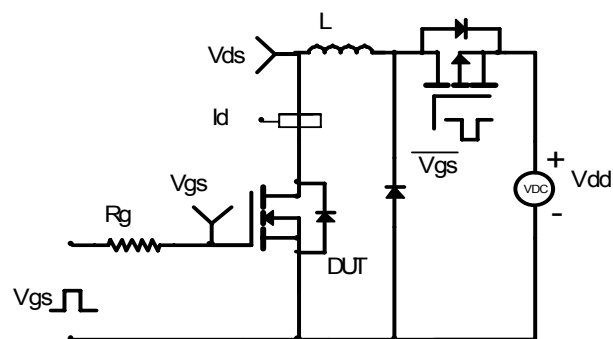
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